Electromagnetic emissions

The NEB NANO is intended for use in the electromagnetic environment specified below. The customer or the user of the NEB NANO should assure that it is used in such an environment.

Emissions test	Compliance	Electromagnetic environment – guidance
RF emissions CISPR 11	Group 1	The NEB NANO uses RF energy only for its internal function. Therefore, its RF emissions are very low and are not likely to cause any interference in nearby electronic equipment.
RF emissions CISPR 11	Class [B]	The NEB NANO is suitable for use in all establishments including domestic and those directly connected to the
Harmonic emissions IEC 61000-3-2	Class A	public low-voltage power supply network that supplies buildings used for domestic purposes.
Voltage fluctuations/ flicker emissions IEC 61000-3-3	Complies	

Electromagnetic immunity

The NEB NANO is intended for use in the electromagnetic environment specified below. The customer or the user of the NEB NANO should assure that it is used in such an environment.

Immunity Test	IEC 60601 Test level	Compliance level	Electromagnetic environment – guidance		
Electrostatic discharge (ESD) IEC 61000-4-2	±8 kV contact ±15 kV air	±8 kV contact ±15 kV air	Floors should be wood, concrete or ceramic tile. If floors are covered with synthetic material, the relative humidity should be at least 30%		
Electrical fast transient/burst IEC 61000-4-4	Power supply lines: ±2 kV input/output lines: ±1 kV	Power supply lines: ±2 kV	Mains power quality should be that of a typical commercial or hospital environment.		
Surge IEC 61000-4-5	line(s) to line(s): ±1 kV. line(s) to earth: ±2 kV. 100 kHz repeti- tion frequency	line(s) to line(s): ±1 kV. 100 kHz repetition frequency	Mains power quality should be that of a typical commercial or hospital environment.		
Voltage dips, short interruptions and voltage variations on power supply input lines IEC 61000-4-11	0% 0.5 cycle At 0°, 45°, 90°, 135°, 180°, 225°, 270° and 315° 0% 1 cycle And 70% 25/30 cycles Single phase: at 0 0% 250 cycle	0% 0.5 cycle At 0°, 45°, 90°, 135°, 180°, 225°, 270° and 315° 0% 1 cycle And 70% 25/30 cycles Single phase: at 0 0% 250 cycle	Mains power quality should be that of a typical commercial or hospital environment.		
Power frequency (50/60Hz) magnetic field IEC 61000-4-8	30 A/m 50Hz/60Hz	30 A/m 50Hz/60Hz	Power frequency magnetic fields should be at levels characteristic of a typical location in a typical commercial or hospital environment.		

Electromagnetic immunity

microlife

The NEB NANO is intended for use in the electromagnetic environment specified below. The customer or the user of the NEB NANO should assure that it is used in such an environment.

Immunity Test	IEC 60601 Test level	Compliance level	Electromagnetic environment – guidance		
Conduced RF IEC61000-4-6	150KHz to 80MHz: 3Vrms 6Vrms (in ISM and amateur radio bands) 80% Am at 1kHz	150KHz to 80MHz: 3Vrms 6Vrms (in ISM and amateur radio bands) 80% Am at 1kHz	Portable and mobile RF communications equipment should be used no closer to any part of the NEB NANO, including cables, than the recommended separation distance calculated from the equation appropriate for the frequency of the transmitter. Recommended separation distances: d=1.2√P; d=2√P		
Radiated RF IEC61000-4-3	10V/m, 80% Am at 1kHz	10V/m, 80% Am at 1kHz	80MHz to 800MHz: d=1.2√P 800MHz to 2.7GHz: d=2.3√P	Where, P is the maximum output power rating of the transmitter in watts (W) according to the transmitter manufacturer, d is the recommended separation distance in meters (m) Field strengths from fixed RF transmitters, as determined by an electromagnetic site survey, should be less than the compliance level in each frequency range. Interference may occur in the vicinity of equipment marked with the following symbol:	

Note 1: At 80 MHz and 800 MHz, the higher frequency range applies.

Note 2: These guidelines may not apply in all situations. Electromagnetic propagation is affected by absorption and reflection from structures, objects and people.

^a Field strengths from fixed transmitters, such as base stations for radio (cellular/cordless) telephones and land mobile radios, amateur radio, AM and FM radio broadcast and TV broadcast cannot be predicted theoretically with accuracy. To assess the electromagnetic environment due to fixed RF transmitters, an electromagnetic site survey should be considered. If the measured field strength in the location in which the NEB NANO is used exceeds the applicable RF compliance level above, the NEB NANO should be observed to verify normal operation. If abnormal performance is observed, additional measures may be necessary, such as re-orienting or relocating the NEB NANO.

^b Over the frequency range 150 kHz to 80 MHz, field strengths should be less than 3 V/m.



Recommended separation distances between portable and mobile RF communications equipment and the NEB NANO

The NEB NANO is intended for use in an electromagnetic environment in which radiated RF disturbances are controlled. The customer or the user of the NEB NANO can help prevent electromagnetic interference by maintaining a minimum distance between portable and mobile RF communications equipment (transmitters) and the NEB NANO as recommended below, according to the maximum output power of the communications equipment.

Rated maximum output power of transmitter W	Separation distance according to frequency of transmitter m					
	150 kHz to 80 MHz (out ISM and amateur radio bands) d=1.2√p	150 kHz to 80 MHz (in ISM and amateur radio bands) d=2√p	80MHz to 800MHz d=1.2√p	800MHz to 2.7GHz d=2.3√p		
0,01	0.12	0.2	0.12	0.23		
0,1	0.38	0.632	0.38	0.73		
1	1.2	2	1.2	2.3		
10	3.8	6.32	3.8	7.3		
100	12	20	12	23		

For transmitters rated at a maximum output power not listed above, the recommended separation distance d in metres (m) can be estimated using the equation applicable to the frequency of the transmitter, where P is the maximum output power rating of the transmitter in watts (W) according to the transmitter manufacturer.

Note 1: At 80 MHz and 800 MHz, the separation distance for the higher frequency range applies.

Note 2: These guidelines may not apply in all situations. Electromagnetic propagation is affected by absorption and reflection from structures, objects and people.

NEB NANO - Guidance and manufacturer's declaration



Electromagnetic immunity

The NEB NANO is intended for use in the electromagnetic environment specified below. The customer or the user of the NEB NANO should assure that it is used in such an environment.

Radiated RF IEC61000-4-3 (Test specifications for ENCLOSURE PORT IMMUNITY to RF wireless communi- cations equipment)	Test Frequency (MHz)	Band a) (MHz)	Service a)	Modulation b)	Modulation b) (W)	Distance (m)	Immunity Test Level (V/m)
	385	380 - 390	TETRA 400	Pulse modulation b) 18 Hz	1,8	0,3	27
	450	380 - 390	GMRS 460, FRS 460	FM c) ± 5 kHz deviation 1 kHz sine	2	0,3	28
	710	704 -	LTE Band 13, 17	Pulse modulation b) 217 Hz	0,2	0,3	9
	745	787					
	780						
	810	800 – 960	GSM 800/900, TETRA 800, iDEN 820, CDMA 850, LTE Band 5	Pulse modulation b) 18 Hz	2	0,3	28
	870	-					
	930						
	1720	1700 – 1990	GSM 1800; CDMA 1900; GSM 1900; DECT; LTE Band 1, 3, 4, 25; UMTS	Pulse modulation b) 217 Hz	2	0,3	28
	1845						
	1970						
	2450	2400 – 2570	Bluetooth, WLAN, 802.11 b/g/n, RFID 2450, LTE Band 7	Pulse modulation b) 217 Hz	2	0,3	28
	5240	5100 – 5800	WLAN 802.11 a/n	Pulse	0,2	0,3	9
	5240			modulation b) 217 Hz			
	5785						

Note: If necessary to achieve the **Immunity Test Level**, the distance between the transmitting antenna and the **ME Equipment** or **ME System** may be reduced to 1 m. The 1 m test distance is permitted by IEC 61000-4-3.

- a) For some services, only the uplink frequencies are included.
- b) The carrier shall be modulated using a 50% duty cycle square wave signal.
- c) As an alternative to FM modulation, 50% pulse modulation at 18 Hz may be used because while it does not represent actual modulation, it would be worst case.

The **Manufacturer** should consider reducing the minimum separation distance, based on **Risk Management**, and using higher **Immunity Test Levels** that are appropriate for the reduced minimum separation distance. Minimum separation distances for higher **Immunity Test Levels** shall be calculated using the following equation: $E=\frac{6}{3}$, P

Where P is the maximum power in W, d is the minimum separation distance in m, and E is the **Immunity Test Level** in V/m.

LT EMC-declaration-A4_NEB NANO EN 0524